AmZ8120

Octal D-Type Flip-Flop with Clear, Clock Enable and 3-State Control

DISTINCTIVE CHARACTERISTICS

- Buffered common clock enable input
- Buffered common asynchronous clear input
- Three-state outputs
- 8-bit, high-speed parallel register with positive edge-triggered, D-type flip-flops
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

The AmZ8120 is an 8-bit register built using advanced Low-Power Schottky technology. The register consists of eight D-type flip-flops with a buffered common clock, a buffered common clock enable, a buffered asynchronous clear input, and three-state outputs.

When the clear input is LOW, the internal flip-flops of the register are reset to logic 0 (LOW), independent of all other inputs. When the clear input is HIGH, the register operates in the normal fashion.

When the three-state output enable ($\overline{OE}$) input is LOW, the Y outputs are enabled and appear as normal TTL outputs. When the output enable ($\overline{OE}$) input is HIGH, the Y outputs are in the high impedance (three-state) condition. This does not affect the internal state of the flip-flop Q output.

The clock enable input ($\overline{E}$) is used to selectively load data into the register. When the $\overline{E}$ input is HIGH, the register will retain its current data. When the $\overline{E}$ is LOW, new data is entered into the register on the LOW-to-HIGH transition of the clock input.

This device is packaged in a slim 24-pin package (0.3 inch row spacing).

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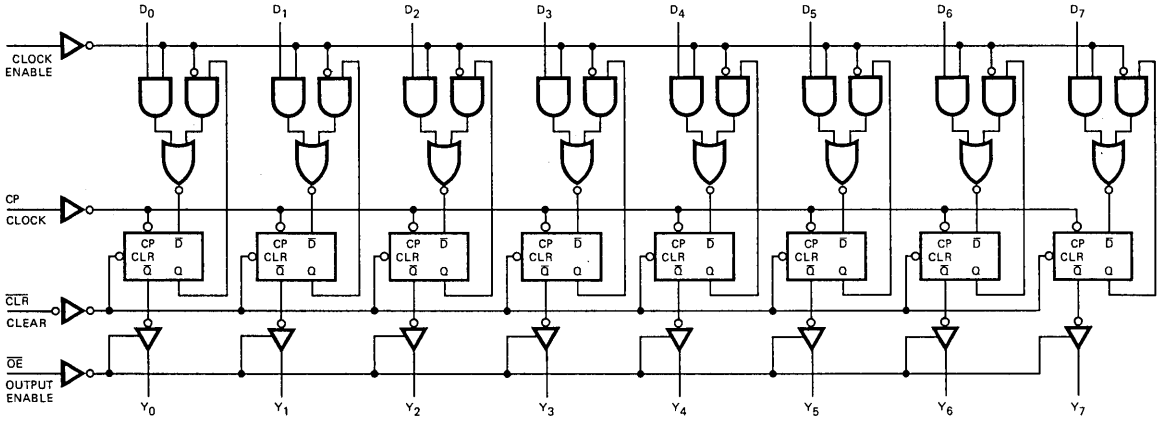
LOGIC DIAGRAM



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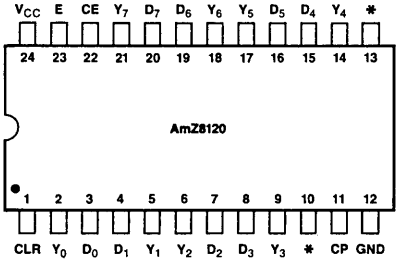
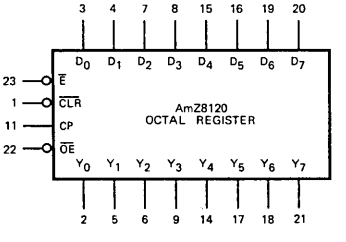
CONNECTION DIAGRAM
Top View



Note: Pin 1 is marked for orientation. *Reserved – do not use.

LOGIC SYMBOL



V_{CC} = Pin 24
GND = Pin 12

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ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L	$T_A = 0°C$ to $+70°C$	$V_{CC} = 5.0V \pm 5\%$	MIN. = 4.75 V	MAX. = 5.25 V
MIL	$T_A = -55°C$ to $+125°C$	$V_{CC} = 5.0V \pm 10\%$	MIN. = 4.50 V	MAX. = 5.50 V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)		Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	V_{CC} = MIN., $V_{IN} = V_{IH}$ or V_{IL}	MIL, $I_{OH} = -1.0mA$	2.4	3.4		Volts
			COM'L, $I_{OH} = -2.6mA$	2.4	3.4		
V_{OL}	Output LOW Voltage	V_{CC} = MIN., $V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 4.0mA$			0.4	Volts
			$I_{OL} = 8.0mA$			0.45	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs		2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL			0.7	Volts
			COM'L			0.8	
V_I	Input Clamp Voltage	V_{CC} = MIN., $I_{IN} = -18mA$				−1.5	Volts
I_{IL}	Input LOW Current	V_{CC} = MAX., $V_{IN} = 0.4V$				−0.36	mA
I_{IH}	Input HIGH Current	V_{CC} = MAX., $V_{IN} = 2.7V$				20	μA
I_I	Input HIGH Current	V_{CC} = MAX., $V_{IN} = 7.0V$				0.1	mA
I_O	Off-State (High-Impedance) Output Current	V_{CC} = MAX.	$V_O = 0.4V$			−20	μA
			$V_O = 2.4V$			20	
I_{SC}	Output Short Circuit Current (Note 3)	V_{CC} = MAX.		−15		−85	mA
I_{CC}	Power Supply Current (Note 4)	V_{CC} = MAX.			24	37	mA

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical limits are at $V_{CC} = 5.0V$, 25°C ambient and maximum loading.
3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
4. All outputs open, $\overline{E}$ = GND, Di inputs = CLR = $\overline{OE}$ = 4.5V. Apply momentary ground, then 4.5V to clock input.

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MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	−65°C to +150°C
Temperature (Ambient) Under Bias	−55°C to +125°C
Supply Voltage to Ground Potential Continuous	−0.5 V to +7.0 V
DC Voltage Applied to Outputs for High Output State	−0.5 V to +V_{CC} max.
DC Input Voltage	−0.5 V to +7.0 V
DC Output Current, Into Outputs	30 mA
DC Input Current	−30 mA to +5.0 mA

SWITCHING CHARACTERISTICS

(T_A = +25°C, V_{CC} = 5.0V)

Parameters	Description		Min.	Typ.	Max.	Units	Test Conditions
t_{PLH}	Clock to Y_i ($\overline{OE}$ LOW)			18	27	ns	C_L = 15pF, R_L = 2.0kΩ
t_{PHL}				24	36		
t_{PHL}	Clear to Y			22	35	ns	
t_s	Data (D_i)		10	3		ns	
t_h	Data (D_i)		10	3		ns	
t_s	Enable ($\overline{E}$)	Active	15	10		ns	
		Inactive	20	12			
t_h	Enable ($\overline{E}$)		0	0		ns	
t_s	Clear Recovery (In-Active) to Clock		11	7		ns	
t_{pw}	Clock	HIGH	20	14		ns	
		LOW	25	13			
t_{pw}	Clear		20	13		ns	
t_{ZH}	$\overline{OE}$ to Y_i			9	13	ns	
t_{ZL}				14	21		
t_{HZ}	$\overline{OE}$ to Y_i			20	30	ns	C_L = 5.0pF, R_L = 2.0kΩ
t_{LZ}				24	36		
f_{max}	Maximum Clock Frequency (Note 1)			40		MHz	

Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r, t_f, pulse width or duty cycle.

SWITCHING CHARACTERISTICS OVER OPERATING RANGE*

Parameters	Description		COM'L T_A = 0°C to +70°C, V_{CC} = 5.0V ± 5% Min.	COM'L Max.	MIL T_A = −55°C to +125°C, V_{CC} = 5.0V ± 10% Min.	MIL Max.	Units	Test Conditions
t_{PLH}	Clock to Y_i ($\overline{OE}$ LOW)			33		39	ns	C_L = 50pF, R_L = 2.0kΩ
t_{PHL}				45		54		
t_{PHL}	Clear to Y			43		51	ns	
t_s	Data (D_i)		12		15		ns	
t_h	Data (D_i)		12		15		ns	
t_s	Enable ($\overline{E}$)	Active	17		20		ns	
		Inactive	20		23			
t_h	Enable ($\overline{E}$)		0		0		ns	
t_s	Clear Recovery (In-Active) to Clock		13		15		ns	
t_{pw}	Clock	HIGH	25		30		ns	
		LOW	30		35			
t_{pw}	Clear		22		25		ns	
t_{ZH}	$\overline{OE}$ to Y_i			19		25	ns	
t_{ZL}				30		39		
t_{HZ}	$\overline{OE}$ to Y_i			35		40	ns	C_L = 5.0pF, R_L = 2.0kΩ
t_{LZ}				39		42		
f_{max}	Maximum Clock Frequency (Note 1)		25		20		MHz	

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

DEFINITION OF FUNCTIONAL TERMS

D_i The D flip-flop data inputs.

$\overline{CLR}$ When the clear input is LOW, the Q_i outputs are LOW, regardless of the other inputs. When the clear input is HIGH, data can be entered into the register.

CP Clock Pulse for the Register; enters data into the register on the LOW-to-HIGH transition.

Y_i The register three-state outputs.

$\overline{E}$ Clock Enable, When the clock enable is LOW, data on the D_i input is transferred to the Q_i output on the LOW-to-HIGH clock transition. When the clock enable is HIGH, the Q_i outputs do not change state, regardless of the data or clock input transitions.

$\overline{OE}$ Output Control. When the $\overline{OE}$ input is HIGH, the Y_i outputs are in the high impedance state. When the $\overline{OE}$ input is LOW, the TRUE register data is present at the Y_i outputs.

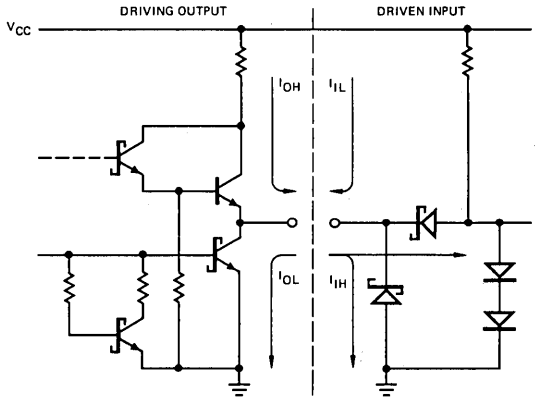
FUNCTION TABLE

	Inputs					Internal	Outputs
Function	$\overline{OE}$	$\overline{CLR}$	$\overline{E}$	D_i	CP	Q_i	Y_i
Hi-Z	H	X	X	X	X	X	Z
Clear	H	L	X	X	X	L	Z
	L	L	X	X	X	L	L
Hold	H	H	H	X	X	NC	Z
	L	H	H	X	X	NC	NC
Load	H	H	L	L	↑	L	Z
	H	H	L	H	↑	H	Z
	L	H	L	L	↑	L	L
	L	H	L	H	↑	H	H

H = HIGH
L = LOW
X = Don't Care

NC = No Change
↑ = LOW-to-HIGH Transition
Z = High Impedance

LOW-POWER SCHOTTKY INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



Note: Actual current flow direction shown.

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